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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/628,890	BIEGANEK ET AL.	
Examiner	Art Unit	
Yaritza Guadalupe McCall	2859	_

SEARCHED			
Class	Subclass	Date	Examiner
33	512, 514.2	6/6/2005	YG
33	515	6/6/2005	YG
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Previous searches updated	6/6/2005	YG	
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